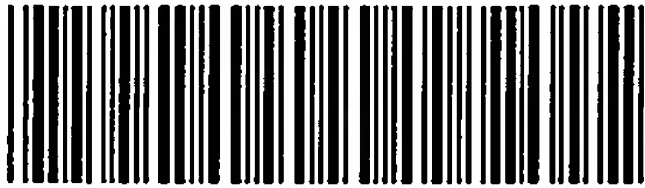


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/655,972	PAN ET AL.	
	Examiner	Art Unit	
	Binh X. Tran	1765	

SEARCHED			
Class	Subclass	Date	Examiner
438	700	9/9/2005	BT
438	710	9/9/2005	BT
438	712	9/9/2005	BT
438	715	9/9/2005	BT

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
438	700	9/9/2005	BT
438	710	9/9/2005	BT
438	712	9/9/2005	BT
438/715		9/9/2005	BT

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Update search using USPAT, USPG-PUB, EPO, JPO, DERWENT databases	9/9/2005	BT